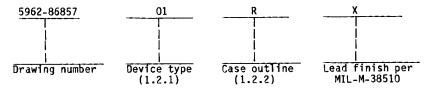


1	SCOP	1

- 1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".
  - 1.2 Part number. The complete part number shall be as shown in the following example:



1.2.1 Device type. The device type shall identify the circuit function as follows:

Device type Generic number Circuit function 01 544CT698 8-bit magnitude comparator with LS TTL compatible inputs

1.2.2 Case outline. The case outline shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter

Case outline

R

D-8 (20-lead, 1/4" x 1-1/16"), dual-in-line package.

1.3 Absolute maximum ratings. 1/

Supply voltage range	-0.5 V dc to +7.0 V dc
DC input voltage	-0.5 V dc to V <sub>CC</sub> +0.5 V dc
DC output voltage	-0.5 V dc to V <sub>CC</sub> +0.5 V dc -0.5 V dc to V <sub>CC</sub> +0.5 V dc
Clamp diode current	±20 mA
DC output current (per pin)	±25 mA
DC Vcc or GND current (per pin)	±50_mA
Storage temperature range	-65°C to +150°C
Maximum power dissipation, (PD)	500 mW 2/
Lead temperature (soldering, 10 seconds)	+260°C -
Thermal resistance, junction-to-case (0,1c):	
Case R	See MIL-M-38510, appendix C
Junction temperature $(T_J)$	+175°C
Recommended operating conditions.	

1.4

Supply voltage ( $V_{CC}$ )	+4.5 V dc to +5.5 V dc
Case operating temperature range $(T_C)$	-55°C to +125°C
Input rise or fall time:	
V <sub>CC</sub> = 4.5 V	0 to 500 ns

- 1/ Unless otherwise specified, all voltages are referenced to ground.
- 2/ For  $T_C = +100^{\circ}C$  to  $+125^{\circ}C$ , derate linearly at 12 mW/ $^{\circ}C$ .

MILITARY DRAWING	SIZE	14933	DWG NO.	5952-95857	
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO		REV		PAGE	2

## 2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

**SPECIFICATION** 

MILITARY

MIL-M-38510

Microcircuits, General Specification for.

**STANDARD** 

MILITARY

MIL-STD-883

Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

## 3. REQUIREMENTS

- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
  - 3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.
- 3.2.2 Truth table and logic diagram. The truth table and logic diagram shall be as specified on figure 2.
  - 3.2.3 Case outline. The case outline shall be in accordance with 1.2.2 herein.
- 3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table  $\overline{I}$  and apply over the full recommended case operating temperature range.
- 3.4 Marking. Marking shall be in accordance with MIL-STD-983 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 5.4 herein.
- 3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

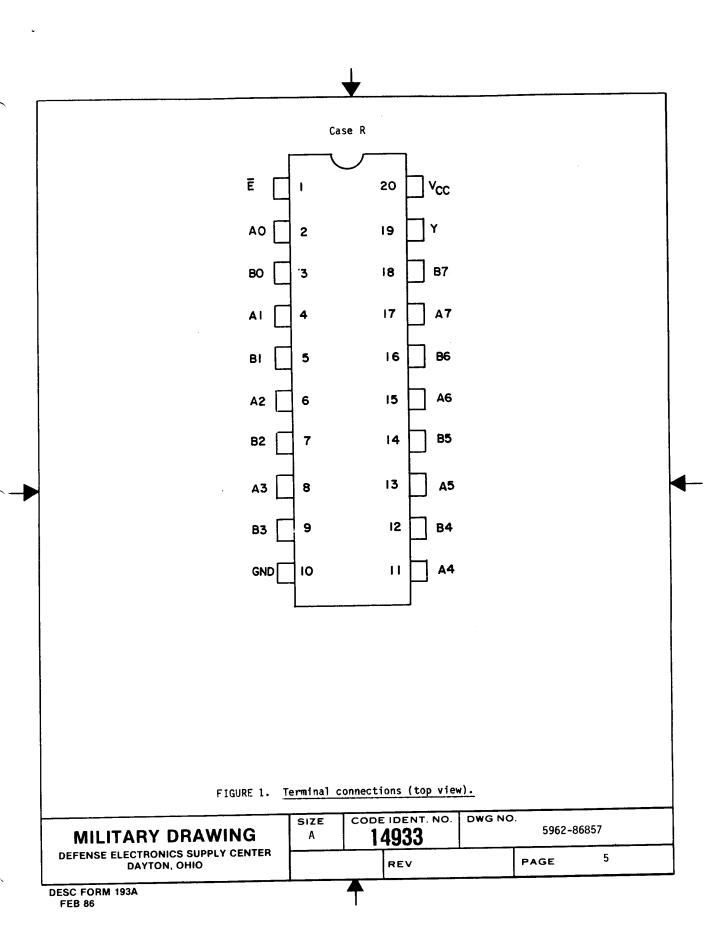
## MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO SIZE CODE IDENT. NO. DWG NO. 14933 5962-86857 REV PAGE 3

Test	Symbol	Conditions 1/ -55°C < T <sub>C</sub> < +125°C	Group A	Lin	nits	Unit
		Conditions 1/ $-55^{\circ}C \leq T_{C} \leq +125^{\circ}C$ $4.5 \text{ V dc } \leq V_{CC} \leq 5.5 \text{ V dc}$ $\text{(Unless otherwise specifie}$	subgroups d)	Min	Max	Ī
High level output voltage	v <sub>он</sub>	$ V_{IN}=V_{IH}$ or $ I_0  \le 20 \mu A$		4.4     4.4		[   V 
	1	$V_{CC} = 4.5 \text{ V}$ $ II_0  \leq 4.0 \text{ m}$	A	3.7		Ī
Low-level output voltage	Ţ V <sub>OL</sub>	V <sub>IN</sub> =V <sub>IH</sub> or   I <sub>0</sub>   ≤ 20 µA			0.1	ļ
	 	V <sub>CC</sub> = 4.5 V   T <sub>0</sub>   < 4.0 m	A		0.4	ł   
High-level input voltage	VIH	+4.5 V < V <sub>CC</sub> < +5.5 V	<u>'</u>	2.0		i i
Low-level input voltage	VIL	1+4.5 V < VCC < +5.5 V	<u>i</u>		0.8	İ
Input leakage current	IIN	V <sub>CC=</sub> 5.5 V; V <sub>IN=</sub> V <sub>CC</sub> or GND		-1.0	1.0	μА
Quiescent current	Icc	V <sub>CC</sub> =5.5 V; V <sub>IN</sub> =V <sub>CC</sub> or GND		i	160	
Additional quiescent supply current	1 <sub>CC</sub>	$V_{IN}=2.4$ V or 0.5 V, any 1 inp $V_{IN}=V_{CC}$ or GND, other inputs $V_{CC}=5.5$ V; $I_{OUT}=0$ $\mu$ A	ut i		1.8	mA 
Input capacitance	CIN		4		10	pF
Functional tests	i I	  See 4.3.1d	1 7 1	 	i	
Propagation delay time, A or B to output	t <sub>PHL1</sub> ,	$V_{CC} = 5.0 \text{ V } \pm 10\%$ $ C_{C}  = 50 \text{ pF } \pm 10\%$	9		35	ns
s. b oo oa opa v	t <sub>PLH1</sub>	See figure 3	10,11		53	
Propagation delay time, output enable to any	tpHL2,	-j -l -	9	İ	24	
output	tpLH2		10,11	i	36	
Output transition time 2/	t <sub>THL</sub> ,		9	İ	15	_
	I  t <sub>TLH</sub>		10,11		22	

<sup>1/</sup> For a power supply of 5 V ±10% the worst case output voltages (V $_{OH}$  and V $_{OL}$ ) occur for HCT at 4.5 V. Thus the 4.5 V values should be used when designing with this supply. Worst case V $_{IH}$  and V $_{IL}$  occur at V $_{CC}$  = 5.5 V and 4.5 V respectively.

MILITARY DRAWING	SIZE A	14933	DWG NO. 5962-86	5857
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO		REV	PAGE	4

 $<sup>\</sup>underline{2}/$  Transition times (t<sub>THL</sub>, t<sub>TLH</sub>), if not tested, shall be guaranteed to the specified parameters.



Truth table

Inputs	•	Outputs
A == B	Ē	Υ
A = B A ≠ B X	L L H	L H H

X = Don't care
L = Low level
H = High level

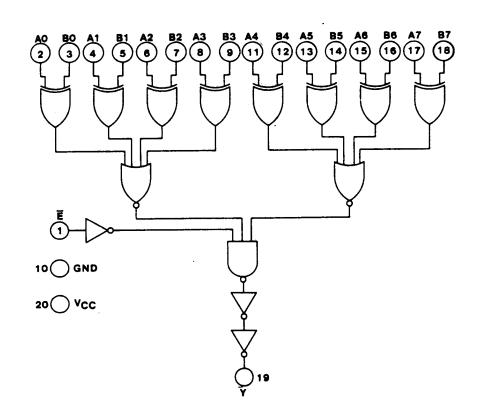


FIGURE 2. Truth table and logic diagram..

MILITARY DRAWING
DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO

SIZE
A
CODE IDENT. NO. DWG NO.
5962-86857

REV
PAGE 6

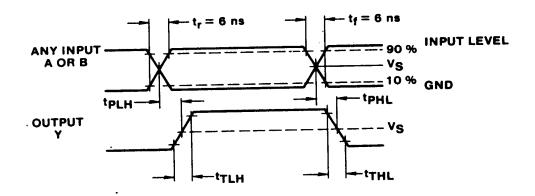


FIGURE 3. Switching time waveforms.

MILITARY DRAWING	SIZE A	14933	DWG NO.	5962-868	357
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO		REV		PAGE	7

- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-983 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.8 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.
  - 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-983, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
  - a. Burn-in test (method 1015 of MIL-STD-883).
    - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
    - (2)  $T_A = +125^{\circ}C$ , minimum.
  - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
  - 4.3.1 Group A inspection.
    - a. Tests shall be as specified in table II herein.
    - b. Subgroups 5, 6, and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.
    - c. Subgroup 4 ( $C_{\rm IN}$  measurement) shall be measured only for the initial test and after process or design changes which may affect input capacitance.
    - d. Subgroup 7 tests sufficiently to verify the truth table.
  - 4.3.2 Groups C and D inspections.
    - a. End-point electrical parameters shall be as specified in table II herein.
    - b. Steady-state life test (method 1005 of MIL-STD-883) conditions:
      - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
      - (2)  $T_A = +125^{\circ}C$ , minimum.
      - (3) Test duration: 1,000 hours, except as permitted by appendix B of MIL-M-38510 and method 1005 of MIL-STD-983.

MILITARY DRAWING	SIZE	14933	D <b>W</b> G NO. 5962-86857
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO		REV	PAGE 9

## TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method   5005, table I)
	1
Final electrical test parameters     (method 5004)	1*,2,3,9
Group A test requirements   (method 5005)	1,2,3,4,7,9, 10,11
Groups C and D end-point   electrical parameters   (method 5005)	1,2,3
Additional electrical subgroups   for group C periodic inspections	

<sup>\*</sup>PDA applies to subgroup 1.

- 5. PACKAGING
- 5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-39510.
- 6. NOTES
- 6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
- 6.2 Replaceability. Replaceability is determined as follows: Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

MILITARY DRAWING
DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO

SIZE CODE IDENT. NO. DWG NO. 14933 5962-86857

REV PAGE 9

6.4 Approved sources of supply. Approved sources of supply are listed herein. Additional sources will be added as they become available. The vendors listed herein have agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor   CAGE   number	Vendor   similar part   number 1/
5962-8685701RX	18714	   CD544CT588F/3A   MM54HCT688J/883

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number	Vendor name and address
18714	RCA Corporation Route 202 Somerville, NJ 08875
27014	National Semiconductor 2900 Semiconductor Drive Santa Clara, CA 95051

MILITARY DRAWING
DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO

SIZE
CODE IDENT. NO. DWG NO.

14933
5962-86857

REV
PAGE 19